EXHIBIT C

MICRON CONSTRUCTIONS

Micron Defendants' Proposed Constructions of Disputed Claim Terms and Supporting Evidence

'912 Patent

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
'912: All asserted claims	"rank"	"an independent set of one or more memory devices on a memory module that act together in response to command signals, including chip select signals, to read or write the full bit-width of the memory module"
		Intrinsic Evidence
		<u>U.S. Patent No. 7619912</u>
		2:16-42; 2:59-3:14; 3:32–48; 6:31-38; 6:55-9:21; 10:31–55; 11:43-23:25; 23:60-24:38; 25:27-44; 32:27-38; Figs 1A, 1B, 2A, 2B, 3A, 3B, 11A, 11B.
		JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004.
		File Histories ¹
		File histories of U.S. Patents: No. 7619912, No. 7286436, No. 7289386, No. 7532537, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No.
		8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No.

¹ Reference to a file history is intended to refer to all papers in the file history, including but not limited to non-final and final office actions, applicant/examiner interviews, terminal disclaimers, applicant responses to all office actions, amendments, and requests for continued examination.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		9037809, No. 9318160, No. 9858215, No. 9846659, No. 11093417, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893
		File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415
		Inter Partes Reviews ²
		IPR2014-00882 (<i>see</i> , <i>e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see</i> , <i>e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00063, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615 (<i>see e.g.</i> , Paper 1 (Petition) at 11–14, 28–32, 38–51, 53–57, 74–77, 86–95, and 99–102, including all evidence cited therein: Paper 7 (POPR) at 28, 34, 40, 43, and 62, 69, including all evidence
		evidence cited therein; Paper 7 (POPR) at 28–34, 40–43, and 62–69, including all evidence cited therein, Paper 20 (Institution Decision) at 28–33, and 43–45, including all evidence cited therein), IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00847, IPR2023-00883

² Reference to an *Inter Partes* Review (IPR) is intended to refer to all papers associated with the IPR, including but not limited to the petition, patent owner preliminary response, patent owner response, petitioner reply, patent owner sur-reply, institution decision, final written decision, and all exhibits.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Inter Partes Reexaminations ³ No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758 Federal Circuit Appeals ⁴ No. 15-126, No. 15-1179, No. 16-1742 (see, e.g., Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (see, e.g., Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (see, e.g., Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114 Extrinsic Evidence District Court Cases ⁵

³ Reference to an *Inter Partes* Reexamination is intended to refer to all papers associated with the reexamination, including but not limited to all non-final and final actions, patent owner responses, briefs, communications, and exhibits.

⁴ Reference to a Federal Circuit appeal is intended to refer to all materials associated with the appeal, including but not limited to briefs, motions, replies, orders, decisions, and appendices.

⁵ Reference to a district court case is intended to refer to all materials associated with the litigation, including but not limited to briefs, pleadings, motions, disclosures, replies, orders, decisions, and appendices.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.) (see., e.g., Dkt. No. 45, Exhibit A at 1), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JESD 205 Standard, JESD 82-20A Standard, JESD 206 Standard, JESD 79-2F Standard, JEDEC Standard No. 21C, JEDEC No. 21C Specification for DDR3 LRDIMM, JESD 82-30 Standard, JESD 79-3F Standard, JESD 248A Standard, JESD 79-4 Standard, JESD 82-31A Standard, JESD 79-4-1B Standard, JESD 79-4C Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)

⁶ Reference to an International Trade Commission (ITC) Investigation is intended to refer to all materials associated with the ITC investigation, including but not limited to briefs, motions, replies, orders, decisions, and appendices.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Defendants Samsung Electronics Co., Ltd., Samsung Electronics America, Inc., and Samsung Semiconductor, Inc. (collectively, "Samsung Defendants") in the Lead Case, including but not limited to, any expert testimony.
'912: 16	"row[/column] address signal"	"a varying electrical impulse that conveys an address of either a row or a column of memory locations from one point to another"
	'912 patent: all claims	Intrinsic Evidence
		<u>U.S. Patent No. 7619912</u>
		5:22-45; 6:55-64; 7:36-11:42; 12:11-20:63; 21:13-22:63; Figures 1A, 1B, 2A, 2B, 3A, and 3B.
		JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004.
		File Histories
		File histories of U.S. Patents: No. 7619912, No. 7286436, No. 7289386, No. 7532537, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 11093417, No. 10902886, No.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893
		File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415
		Inter Partes Reviews
		IPR2014-00882 (<i>see</i> , <i>e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see</i> , <i>e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00639, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-01427, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00847, IPR2023-00883
		Inter Partes Reexaminations
		No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758
		Federal Circuit Appeals

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.) (<i>see.</i> , <i>e.g.</i> , Dkt. No. 45, Exhibit A at 1), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		JEDEC Standards: JESD 205 Standard, JESD 82-20A Standard, JESD 206 Standard, JESD 79-2F Standard, JEDEC Standard No. 21C, JEDEC No. 21C Specification for DDR3 LRDIMM, JESD 82-30 Standard, JESD 79-3F Standard, JESD 248A Standard, JESD 79-4 Standard, JESD 82-31A Standard, JESD 79-4-1B Standard, JESD 79-4C Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)
		The Penguin Dictionary of Electronics ("signal")
		Collins Dictionary Electronics: Definitions for the Digital Age ("signal")
		Microsoft Computer Dictionary, Fifth edition 2002 ("signal")
		McGraw-Hill Dictionary of Electrical and Computer Engineering, Sixth Edition, at p. 9 ("address") (2003)
		Newton's Telecom Dictionary, 19th Edition, at pp. 44–45 ("address"), 721 ("signal") (2003)
		Wiley Electrical and Electronics Engineering Dictionary, IEEE Press, at pp. 14 ("address"), 125 ("column"), 673 ("row") (2004)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'912: 15, 16, 28, 86, 88	"coupled to the printed circuit board"	"electrically connected to the printed circuit board."
		Intrinsic Evidence
	'912 patent: 15, 16, 28, 86, 88	<u>U.S. Patent No. 7619912</u>
		2:45-59; 3:15-29; 4:25–28; 5:6-55; 6:4-11; 21:36-24:58; 25:26-44; 26:2-28; 28:13-24; 28:45-58; 29:1-30; 30:22-31:23; 31:56-32:3; Figures 1A, 1B, 2A, 2B, 3A, 6A, 10, 11A, 11B
		JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004.
		<u>File Histories</u>
		File histories of U.S. Patents: No. 7619912, No. 7286436, No. 7289386, No. 7532537, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 11093417, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893
		File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415
		Inter Partes Reviews

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		IPR2014-00882 (<i>see</i> , <i>e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see</i> , <i>e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01374, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2028-0064, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00063, IPR2022-00064, IPR2022-00037, IPR2022-000615, IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00737, IPR2022-00615, IPR2022-00999, IPR2022-00741, IPR2022-01428, IPR2023-00203, IPR2023-00996, IPR2023-00405, IPR2023-00883 **Inter Partes** Reexaminations** No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758 **Federal Circuit Appeals** No. 15-126, No. 15-1179, No. 16-1742 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-274, No. 16-666, No. 17-1617, No. 17-1618, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.) (see., e.g., Dkt. No. 45, Exhibit A at 1), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JESD 205 Standard, JESD 82-20A Standard, JESD 206 Standard, JESD 79-2F Standard, JEDEC Standard No. 21C, JEDEC No. 21C Specification for DDR3 LRDIMM, JESD 82-30 Standard, JESD 79-3F Standard, JESD 248A Standard, JESD 79-4 Standard, JESD 82-31A Standard, JESD 79-4-1B Standard, JESD 79-4C Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
'912: 1, 39, 77, 80, 82, 90	"mounted to the printed circuit board"	McGraw-Hill Dictionary of Electrical and Computer Engineering, Sixth Edition, at p. 124 ("couple") (2003) Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty. Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony. "attached to the printed circuit board" Intrinsic Evidence U.S. Patent No. 7619912 1:25-34; 2:46-3:28; 4:25-28; 5:5-7:53; 21:36-24:58; 28:13-44; 31:24-31; Figures 1A, 1B, 2A, 2B, 3A, 10, 11A, 11B. JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004. File Histories File histories of U.S. Patents: No. 7619912, No. 7286436, No. 7289386, No. 7532537, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No.
		8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 11093417, No. 10902886, No.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893
		File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415
		Inter Partes Reviews
		IPR2014-00882 (<i>see</i> , <i>e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see</i> , <i>e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00063, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00883
		Inter Partes Reexaminations
		No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758
		Federal Circuit Appeals

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.) (see., e.g., Dkt. No. 45, Exhibit A at 1), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		JEDEC Standards: JESD 205 Standard, JESD 82-20A Standard, JESD 206 Standard, JESD 79-2F Standard, JEDEC Standard No. 21C, JEDEC No. 21C Specification for DDR3 LRDIMM, JESD 82-30 Standard, JESD 79-3F Standard, JESD 248A Standard, JESD 79-4 Standard, JESD 82-31A Standard, JESD 79-4-1B Standard, JESD 79-4C Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)
		Wiley Electrical and Electronics Engineering Dictionary, IEEE Press, at p. 484 ("mount") (2004)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'912: 1, 15, 28, 39	"wherein the logic element generates gated column access strobe (CAS) signals or chip-select signals of the output	"the logic element generates gated column access strobe signals or chip-select signals in response at least in part to all four of (i) the at least one row address signal, (ii) the bank address signals, (iii) the at least one chip-select signal of the set of input control signals and (iv) the PLL clock signal"
	[control] signals in response at least in part to (i) the [at least one] row address signal, (ii) the bank	<u>U.S. Patent No. 7619912</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
	address signals, and (iii) the [at least one] chip-	4:42-5:21; 6:55-9:21; 11:43-12:10; 12:12-23:25; 24:1-13; 26:1-27; Figs 1A, 1B, 2A, 2B, 3A, 3B, 11A, 11B.
	select signal of the [set/plurality] of input [control] signals and (iv)	JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004.
	the PLL clock signal"	<u>File Histories</u>
		File histories of U.S. Patents: No. 7619912, No. 7286436, No. 7289386, No. 7532537, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 11093417, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893
		File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415
		Inter Partes Reviews
		IPR2014-00882 (<i>see, e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see, e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062,

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		IPR2022-00063, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00847, IPR2023-00883
		Inter Partes Reexaminations
		No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758
		Federal Circuit Appeals
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.) (<i>see.</i> , <i>e.g.</i> , Dkt. No. 45, Exhibit A at 1), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JESD 205 Standard, JESD 82-20A Standard, JESD 206 Standard, JESD 79-2F Standard, JEDEC Standard No. 21C, JEDEC No. 21C Specification for DDR3 LRDIMM, JESD 82-30 Standard, JESD 79-3F Standard, JESD 248A Standard, JESD 79-4 Standard, JESD 82-31A Standard, JESD 79-4-1B Standard, JESD 79-4C Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
'912: 77	"wherein the logic element responds to at least (i) a row address bit of the at least one row/column address signal, (ii) the bank signals, and (iii) the at least one chip-select signal of the set of input control signals and (iv) the PLL clock by generating a first number of chip-select signals of the set of output control signals, the first number of chip-select signals generated by the logic element equal to the first number of ranks, and the at least one chip-select signal of the set of input control signals comprises a second number of chip-select signals equal to the second number of ranks"	"the logic element generates a number of chip-select signals equal to the first number of ranks in response to all four of (i) a row address bit of the at least one row/column address signal, (ii) the bank address signals, (iii) a number of chip-select signals of the set of input control signals equal to the second number of ranks and (iv) the PLL clock signal" Intrinsic Evidence U.S. Patent No. 7619912 4:42-5:21; 6:55-9:21; 11:43-12:10; 12:12-23:25; 24:1-13; 26:1-27; Figs 1A, 1B, 2A, 2B, 3A, 3B, 11A, 11B. JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004. File Histories File histories of U.S. Patents: No. 7619912, No. 7286436, No. 7289386, No. 7532537, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 11093417, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893 File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415 Inter Partes Reviews

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		IPR2014-00882 (<i>see, e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see, e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2002-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00063, IPR2022-00064, IPR2022-00063, IPR2022-000615, IPR2022-00063, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00999, IPR2022-00711, IPR2022-01428, IPR2022-00737, IPR2022-00996, IPR2023-00205, IPR2023-00405, IPR2023-00883 **Inter Partes Reexaminations** No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758 **Federal Circuit Appeals** No. 15-126, No. 15-1179, No. 16-1742 (**see, e.g.**, Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (**see, e.g.**, Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (**see, e.g.**, Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2744, No. 16-666, No. 17-1617, No. 17-1618, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
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Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.) (see., e.g., Dkt. No. 45, Exhibit A at 1), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JESD 205 Standard, JESD 82-20A Standard, JESD 206 Standard, JESD 79-2F Standard, JEDEC Standard No. 21C, JEDEC No. 21C Specification for DDR3 LRDIMM, JESD 82-30 Standard, JESD 79-3F Standard, JESD 248A Standard, JESD 79-4 Standard, JESD 82-31A Standard, JESD 79-4-1B Standard, JESD 79-4C Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'912: 80	"wherein the generation of the first number of chip- select signals of the output control signals by the logic	"the logic element generates the first number of chip-select signals in response at least in part to all four of (i) the at least one row address signal, (ii) the bank address signals, (iii) the at least one chip-select signal of the set of input control signals and (iv) the PLL clock signal"
	element is based on the	Intrinsic Evidence
	logic element responsive at least in part to (i) the at	<u>U.S. Patent No. 7619912</u>
	least one row address signal, (ii) the bank address signals, and (iii) the at least one chip-select signal of	4:42-5:21; 6:55-9:21; 11:43-12:10; 12:12-23:25; 24:1-13; 26:1-27; Figs 1A, 1B, 2A, 2B, 3A, 3B, 11A, 11B.
	the set of input control signals received by the logic element and (iv) the	JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004.
	clock signals received from the phase-lock loop	<u>File Histories</u>
	device"	File histories of U.S. Patents: No. 7619912, No. 7286436, No. 7289386, No. 7532537, No.
		7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No.
		8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No.
		8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 11093417, No. 10902886, No.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893
		Inter Partes Reviews
		IPR2014-00882 (<i>see</i> , <i>e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see</i> , <i>e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00639, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00847, IPR2023-00883
		Inter Partes Reexaminations
		No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758
		Federal Circuit Appeals
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		(see, e.g., Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.) (see., e.g., Dkt. No. 45, Exhibit A at 1), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JESD 205 Standard, JESD 82-20A Standard, JESD 206 Standard, JESD 79-2F Standard, JEDEC Standard No. 21C, JEDEC No. 21C Specification for DDR3 LRDIMM, JESD 82-30 Standard, JESD 79-3F Standard, JESD 248A Standard, JESD 79-4 Standard, JESD 82-31A Standard, JESD 79-4-1B Standard, JESD 79-4C Standard

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
'912: 82, 86	"wherein the logic element responds to at least the at least one row address signal, the bank address signals, and the at least one chip-select signal of the set of input [control] signals and the PLL clock signal by generating a number of rank-selecting signals of the set of output [control]	Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008) Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002) Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty. Micron may also rely on extrinsic evidence identified by Plaintiff or Defendants Samsung Electronics Co., Ltd., Samsung Electronics America, Inc., and Samsung Semiconductor, Inc. (collectively, "Samsung Defendants") in the Lead Case, including but not limited to, any expert testimony. "the logic element generates a number of rank-selecting signals greater than or equal to double the number of input chip-select signals in response to all four of (i) the at least one row address signal, (ii) the bank address signals, (iii) the at least one chip-select signal of the set of input control signals and (iv) the PLL clock signal" Intrinsic Evidence U.S. Patent No. 7619912 4:42-5:21; 6:55-9:21; 11:43-12:10; 12:12-23:25; 24:1-13; 26:1-27; Figs 1A, 1B, 2A, 2B, 3A, 3B, 11A, 11B.
	signals that is greater than double or equal to double the number of chip-select	JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004. File Histories

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
	signals of the set of input [control] signals"	File histories of U.S. Patents: No. 7619912, No. 7286436, No. 7289386, No. 7532537, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 11093417, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893 File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415 Inter Partes Reviews IPR2014-00882 (see, e.g., POPR (Paper 9) at 5, 17), IPR2014-00883 (see, e.g., POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00692, IPR2017-00577, IPR2017-00587, IPR2017-00560, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2022-00664, IPR2022-00064, IPR2022-00064, IPR2022-00064, IPR2022-00067, IPR2022-00065, IPR2022-000699, IPR2022-00064, IPR2022-00144, IPR2022-000745, IPR2022-000615, IPR2022-000699, IPR2022-001427, IPR2022-001428, IPR2023-000454, IPR2023-00204, IPR2023-00405, IPR2023-00405, IPR2023-00405, IPR2023-00405, IPR2023-00445, IPR2023-004455, IPR2023-004455, IPR2023-00445
		<u>Inter Partes Reexaminations</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758
		Federal Circuit Appeals
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		Extrinsic Evidence
		District Court Cases
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.) (see., e.g., Dkt. No. 45, Exhibit A at 1), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		<u>International Trade Commission Investigations</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JESD 205 Standard, JESD 82-20A Standard, JESD 206 Standard, JESD 79-2F Standard, JEDEC Standard No. 21C, JEDEC No. 21C Specification for DDR3 LRDIMM, JESD 82-30 Standard, JESD 79-3F Standard, JESD 248A Standard, JESD 79-4 Standard, JESD 82-31A Standard, JESD 79-4-1B Standard, JESD 79-4C Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'912: 88	"wherein the logic element responds to at least (i) the row address signal, (ii) the bank address signals, (iii)	"the logic element generates a number of rank-selecting signals greater than or equal to double the number of input chip-select signals in response to all four of (i) the at least one row address signal, (ii) the bank address signals, (iii) the at least one chip-select signal of the set of input control signals and (iv) the PLL clock signal"
	and the one chip-select signal of the set of input control signals and (iv) the	<u>Intrinsic Evidence</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
Claim(s)	PLL clock signal by generating a number of rank-selecting signals of the set of output signals that is greater than double or equal to double the number of chip-select signals of the set of input control signals."	U.S. Patent No. 7619912 4:42-5:21; 6:55-9:21; 11:43-12:10; 12:12-23:25; 24:1-13; 26:1-27; Figs 1A, 1B, 2A, 2B, 3A, 3B, 11A, 11B. JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004. File Histories File histories of U.S. Patents: No. 7619912, No. 7286436, No. 7289386, No. 7532537, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 11093417, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893
		IPR2014-00882 (<i>see, e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see, e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692,

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00063, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00847, IPR2023-00883
		Inter Partes Reexaminations
		No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758
		Federal Circuit Appeals
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Cal.), No. 3:09-cv-05718 (N.D. Cal.) (<i>see.</i> , <i>e.g.</i> , Dkt. No. 45, Exhibit A at 1), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JESD 205 Standard, JESD 82-20A Standard, JESD 206 Standard, JESD 79-2F Standard, JEDEC Standard No. 21C, JEDEC No. 21C Specification for DDR3 LRDIMM, JESD 82-30 Standard, JESD 79-3F Standard, JESD 248A Standard, JESD 79-4 Standard, JESD 82-31A Standard, JESD 79-4-1B Standard, JESD 79-4C Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
'912: 90	"wherein the logic element responds to at least (i) the at least one row signal, (ii) the bank address signals, (iii) and the second number of chip-select signals of the plurality of input signals and (iv) the PLL clock signal by generating the first number of chip-select signals of the plurality of output signals that is greater than double or equal to double the second number of chip-select signals of the plurality of	Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony. "the logic element generates a number of chip select signals greater than or equal to double the number of input chip-select signals in response to all of (i) the at least one row address signal, (ii) the bank address signals, (iii) the second number of chip-select signals of the set of input control signals and (iv) the PLL clock signal" Intrinsic Evidence U.S. Patent No. 7619912 4:42-5:21; 6:55-9:21; 11:43-12:10; 12:12-23:25; 24:1-13; 26:1-27; Figs 1A, 1B, 2A, 2B, 3A, 3B, 11A, 11B. JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004. File Histories
	•	File histories of U.S. Patents: No. 7619912, No. 7286436, No. 7289386, No. 7532537, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 11093417, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893 File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Inter Partes Reviews
		IPR2014-00882 (<i>see</i> , <i>e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see</i> , <i>e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00063, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00883
		Inter Partes Reexaminations
		No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758
		Federal Circuit Appeals
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.) (see., e.g., Dkt. No. 45, Exhibit A at 1), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JESD 205 Standard, JESD 82-20A Standard, JESD 206 Standard, JESD 79-2F Standard, JEDEC Standard No. 21C, JEDEC No. 21C Specification for DDR3 LRDIMM, JESD 82-30 Standard, JESD 79-3F Standard, JESD 248A Standard, JESD 79-4 Standard, JESD 82-31A Standard, JESD 79-4-1B Standard, JESD 79-4C Standard Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'912: All	"A memory module	Preamble not limiting.
Asserted Claims	connectable to a computer system, the memory module comprising"	Plain and ordinary meaning.
	module comprising	<u>Intrinsic Evidence</u>
		<u>U.S. Patent No. 7619912</u>
		Abstract; 2:46-3:28; 3:32–4:37; 4:42–58; 5:6-21; 5:46–6:11, 6:64–7:54; 9:24–12:10; 19:53–22:63; 23:60–24:38; 25:26–26:67; 28:13–57; 29:11–30; 30:22–32:50; Figures 1A, 1B, 2A, 2B, 11A, 11B.
		JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004.
		Extrinsic Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'912: All Asserted	"signal"	"a varying electrical impulse that conveys information from one point to another"
Claims		Intrinsic Evidence
		<u>U.S. Patent No. 7619912</u>
		2:34-3:28; 3:61–64; 5:6-45; 4:1–11; 5:6–45; 6:55-12:10; 12:12-23:25; 23:27-25:67; 26:1-32:26; Figs 1A, 1B, 2A, 2B, 3A, 3B, 4A, 4B, 5, 6A–6E.
		JEDEC standard JESD79D, "Double Data Rate (DDR) SDRAM Specification." published February 2004.
		File Histories
		File histories of U.S. Patents: No. 7619912, No. 7286436, No. 7289386, No. 7532537, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 11093417, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893
		File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415
		<u>Inter Partes Reviews</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		IPR2014-00882 (<i>see</i> , <i>e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see</i> , <i>e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00063, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00847, IPR2023-00883
		 Inter Partes Reexaminations No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758 Federal Circuit Appeals No. 15-126, No. 15-1179, No. 16-1742 (see, e.g., Netlist Opening Brief (Dkt. No. 20) at 8-13,
		30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.) (see., e.g., Dkt. No. 45, Exhibit A at 1), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JESD 205 Standard, JESD 82-20A Standard, JESD 206 Standard, JESD 79-2F Standard, JEDEC Standard No. 21C, JEDEC No. 21C Specification for DDR3 LRDIMM, JESD 82-30 Standard, JESD 79-3F Standard, JESD 248A Standard, JESD 79-4 Standard, JESD 82-31A Standard, JESD 79-4-1B Standard, JESD 79-4C Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		The Penguin Dictionary of Electronics ("signal")
		Collins Dictionary Electronics: Definitions for the Digital Age ("signal")
		Microsoft Computer Dictionary, Fifth edition 2002 ("signal")
		Newton's Telecom Dictionary, 19th Edition, at p. 721 ("signal") (2003)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '912 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.

<u>'215 Patent</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
'215: 1, 21	Preambles:	The preambles are limiting.
	"A memory module operable in a computer	Intrinsic Evidence
	system to communicate	<u>U.S. Patent No. 9858215</u>
	data with a memory controller of the computer system via a memory bus in response to memory	1:42-45; 1:47-53; 2:28-36; 2:59-67; 5:18-32; 5:55-63;6:24-39; 6:60-7:13; 7:14-29; 7:30-39; 8:12-14; 8:27-33; 9:18-35; 9:43-55; 9:56-64; 11:49-55; 11:66-12:4; 12:5-12; 12:13-21; 13:36-49; 14:19-36; 15:4-11; 15:21-29; 15:30-36; 15:46-51; 15:57-16:3; 16:4-11; 17:50-56; 18:55-62; 19:52-67; 20:1-11; 20:12-21; 20:22-24; 22:29-39; 22:42-53; 22:58-64; 23:10-16; 25:38-40;

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
	commands received from the memory controller, the	26:62-65; 27:10-26; 27:67-28:5; 30:5-10; 33:23-29; 36:44-54; Figs. 1, 2, 3A, 3B, 4A, 4B, 8A, 8B, 8C, 8D, 9A, 9B, 10A, 10B, 17A, 17B
	memory commands including a first memory command and a subsequent	<u>File Histories</u>
	second memory command, the first memory command to cause the memory module to receive or output a first data burst and the second memory command	File histories of U.S. Patents: No. 9858215, No. 7286436, No. 7289386, No. 7532537, No. 7619912, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 11093417, No. 9318160, No. 9846659, No. 10902886, No.
	to cause the memory module to receive or output a second data burst, the memory module comprising:"; and	10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893 File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415
	"A method of operating a memory module coupled to a memory controller via a memory bus, the memory module comprising memory integrated circuits arranged in ranks and mounted on a printed circuit board having a	IPR2014-00882 (see, e.g., POPR (Paper 9) at 5, 17), IPR2014-00883 (see, e.g., POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00364,
	plurality of edge connections coupled to the memory bus, the memory integrated circuits	IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00063, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204,

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
	including at least one first memory integrated circuit in a first rank and at least	IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00847, IPR2023-00883
	one second memory integrated circuit in a	Inter Partes Reexaminations
	second rank, the method comprising:"	No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758
		Federal Circuit Appeals
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.),
		Cal.), No. 3:09-cv-05718 (N.D. Cal.), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-
		01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		<u>International Trade Commission Investigations</u>
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JEDEC Standard No. 21C, JEDEC 79-4C Standard, JEDEC 82-31A Standard, JEDEC 79-4-1B Standard, JEDEC 82-32A Standard, JEDEC 79-4C Standard, JESD 79 Standard, JESD 79-2 Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '215 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'215: 1, 14, 21, 26	"rank"	"an independent set of one or more memory devices on a memory module that act together in response to command signals, including chip-select signals, to read or write the full bit-width of the memory module"

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		<u>Intrinsic Evidence</u>
		<u>U.S. Patent No. 9858215</u>
		2:41-47; 2:59-63; 6:9-11; 6:30-36; 7:14-29; 8:12-26; 8:27-38; 9:18-35; 9:56-64; 12:13-17; 12:25-34; 12:35-43; 12:44-59; 12:60-67; 13:1-15; 15:30-56; 15:57-16:3; 16:4-20; 16:22-24; 16:42-62; 16:63-17:12; 17:13-15; 18:30-44; 19:52-67; 20:1-11; 20:12-21; 20:49-63; 20:64-21:6; 22:24-28; 22:35-41; 22:47-57; 27:10-33; 28:27-45; 28:56-29:8; 29:29:27-41; Tables 1, 2; Figs.1, 4A, 4B, 8A, 8B, 8C, 8D, 9A, 9B, 10A, 10B, 11A, 11B
		<u>File Histories</u>
		File histories of U.S. Patents: No. 9858215, No. 7286436, No. 7289386, No. 7532537, No. 7619912, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 11093417, No. 9318160, No. 9846659, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893
		File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415
		Inter Partes Reviews
		IPR2014-00882 (<i>see, e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see, e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562,

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00063, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00847, IPR2023-00883
		No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758 Federal Circuit Appeals
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		Extrinsic Evidence District Court Cases

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JEDEC Standard No. 21C, JEDEC 79-4C Standard, JEDEC 82-31A Standard, JEDEC 79-4-1B Standard, JEDEC 82-32A Standard, JEDEC 79-4C Standard, JESD 79 Standard, JESD 79-2 Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '215 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'215: 1	"operable in a computer system to communicate data"	"configured in a computer system to communicate data" Intrinsic Evidence
		<u>U.S. Patent No. 9858215</u>
		1:47-53; 2:28-36; 2:59-67; 5:18-32; 5:55-63; 6:24-39; 6:60-7:13; 7:14-29; 7:30-39; 8:12-14; 8:27-33; 9:18-35; 9:43-55; 9:56-64; 11:49-55; 11:66-12:4; 12:5-12; 12:13-21; 13:36-49; 14:19-36; 15:4-11; 15:21-29; 15:30-36; 15:46-51; 15:57-16:3; 16:4-11; 17:50-56; 18:55-62; 19:52-67; 20:1-11; 20:12-21; 20:22-24; 22:29-39; 22:42-53; 22:58-64; 23:10-16; 25:38-40; 26:62-65; 27:10-26; 27:67-28:5; 30:5-10; 33:23-29; 36:44-54; Examples 2, 3; Figs. 1, 2, 3A, 3B, 4A, 4B, 8A, 8B, 8C, 8D, 9A, 9B, 10A, 10B, 17A, 17B
		File Histories
		File histories of U.S. Patents: No. 9858215, No. 7286436, No. 7289386, No. 7532537, No. 7619912, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 11093417, No. 9318160, No. 9846659, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893
		File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415
		<u>Inter Partes Reviews</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		IPR2014-00882 (<i>see</i> , <i>e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see</i> , <i>e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00063, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00847, IPR2023-00883
		Inter Partes Reexaminations No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758 Extrinsic Evidence
		District Court Cases No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		Federal Circuit Appeals
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		<u>Others</u>
		JEDEC Standards: JEDEC Standard No. 21C, JEDEC 79-4C Standard, JEDEC 82-31A Standard, JEDEC 79-4-1B Standard, JEDEC 82-32A Standard, JEDEC 79-4C Standard, JESD 79 Standard, JESD 79-2 Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '215 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty. Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'215: 1	"logic configured to respond to the first memory command by	The identified "logic" features in claim 1 are indefinite.
	providing first control	For claim 1, the "logic" features are subject to $\S112$, $\P6$, but there is no disclosure of adequate structure or algorithm for the functions of:
	signals to the buffer to	(i) respond[ing] to the first memory command by providing first control signals to the buffer to
	enable communication of the first data burst between	enable communication of the first data burst between the at least one first memory integrated circuit and the memory controller through the buffer; and
	the at least one first	(ii) further respond[ing] to the second memory command by providing second control signals
	memory integrated circuit and the memory controller through the buffer, wherein	to the buffer to enable communication of the second data burst between the at least one second memory integrated circuit and the memory controller through the buffer.
	the logic is further configured to respond to	Intrinsic Evidence
	the second memory command by providing	No intrinsic evidence because there is no corresponding structure.
	second control signals to the buffer to enable	Extrinsic Evidence
	communication of the second data burst between	Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at
	the at least one second	the time the applications leading to the '215 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the
	memory integrated circuit and the memory controller	time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
	,	discern the boundaries of this claim element with reasonable certainty.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
	through the buffer"	Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'215: 3, 4, 24, 25	"the memory module has an overall CAS latency" / "overall CAS latency of the memory module"	"the delay between: (1) the time when a read command is executed by the memory module, and (2) the time when the first piece of data is made available at an output of the memory module"
	the memory module	Intrinsic Evidence
		<u>U.S. Patent No. 9858215</u>
		20:22-47
		Extrinsic Evidence
		JEDEC Standard, DDR SDRAM Specification, JESD79 (Jun. 2000) (MICNL294-00063707); JEDEC Standard, DDR2 SDRAM Specification, JESD79-2 (Sep. 2003) (MICNL294-00063784); JEDEC Standard, DDR2 SDRAM Specification, JESD79-2A (Jan. 2004) (MICNL294-00063864); DDR SDRAM Registered DIMM Design Specification, Standard No. 21-C, JEDEC Solid State Tech. Corp. (Rev. 1.3, Jan. 2002) (MICNL294-00063625); and Micron Technical Note, DDR2 Posted CAS# Additive Latency (2003) (MICNL294-00063622)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '215 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
'215: 3, 4, 24, 25	"actual operational CAS latency of each of the plurality of memory integrated circuits" / "actual operational CAS latency of the memory integrated circuits"	"the delay between: (1) the time when a read command is executed by each of the plurality of memory integrated circuits, and (2) the time when the first piece of data is made available at an output of each of the plurality of memory integrated circuits" / "the delay between: (1) the time when a read command is executed by the memory integrated circuits, and (2) the time when the first piece of data is made available at an output of the memory integrated circuits" Intrinsic Evidence
		<u>U.S. Patent No. 9858215</u>
		20:22-47
		Extrinsic Evidence
		JEDEC Standard, DDR SDRAM Specification, JESD79 (Jun. 2000) (MICNL294-00063707); JEDEC Standard, DDR2 SDRAM Specification, JESD79-2 (Sep. 2003) (MICNL294-00063784); JEDEC Standard, DDR2 SDRAM Specification, JESD79-2A (Jan. 2004) (MICNL294-00063864); DDR SDRAM Registered DIMM Design Specification, Standard No. 21-C, JEDEC Solid State Tech. Corp. (Rev. 1.3, Jan. 2002) (MICNL294-00063625); and Micron Technical Note, DDR2 Posted CAS# Additive Latency (2003) (MICNL294-00063622)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '215 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
'215 patent: 12, 13, 28, 29	"burst of data strobe	Indefinite
12, 13, 20, 29	signals"	Intrinsic Evidence
		<u>U.S. Patent No. 9858215</u>
		11:38-57; Figs. 1, 6A, 6B, 7, 18, 19
		Extrinsic Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '215 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in
'215: 15	"the at least one of the circuit components"	the Lead Case, including but not limited to, any expert testimony. Indefinite Extrinsic Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '215 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.

'417 Patent

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
'417: 1	Preamble:	The preamble is limiting.
	"A memory module operable in a computer system to communicate data with a memory controller of the computer system via a N-bit wide memory bus in response to read or write memory commands received from the memory controller, the memory bus including address and control signal lines and data signal lines, the memory module comprising:"	Intrinsic Evidence U.S. Patent No. 11093417 1:54-63; 2:34-46; 2:65-3:6; 5:65-6:12; 6:35-50; 7:4-9; 7:40-60; 7:61-8:9; 8:10-32; 8:33-58; 8:59-9:6; 9:7-36; 10:5-30; 10:31-43; 10:44-52; 13:26-45; 13:45-59; 13:60-67; 14:25-36; 15:48-61; 16:31-48; 16:49-17:5; 17:16-24; 17:35-43; 17:44-18:3; 18:4-18; 18:19-35; 19:56-20:3; 20:44-21:9; 21:66-22:14; 22:15-25; 22:26-35; 22:36-62; 23:12-21; 24:26-41; 24:42-54; 24:55-25:3; 25:4-26:6; 26:7-14; 29:21-30:22; 31:29-44; 31:35-32:30; 32:61-33:6; 35:1-28; 38:18-37; 41:39-51; Figs. 1, 2, 3A, 3B, 4A, 4B, 8A, 8B, 8C, 8D, 9A, 9B, 10A, 10B, 17A, 17B. File Histories File histories of U.S. Patents: No. 11093417, No. 7286436, No. 7289386, No. 7532537, No. 7619912, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893 File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415
		<u>Inter Partes Reviews</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		IPR2014-00882 (<i>see</i> , <i>e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see</i> , <i>e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00639, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-01427, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00847, IPR2023-00883
		Inter Partes Reexaminations No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758
		Federal Circuit Appeals No. 15-126, No. 15-1179, No. 16-1742 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see</i> , <i>e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>
		JEDEC Standards: JEDEC Standard No. 21C, JESD 79-4 Standard, JEDEC 82-31A Standard, JEDEC 82-32A Standard, JESD 248A Standard, JEDEC 79-4C Standard, JESD 79 Standard, JESD 79-2 Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '417 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'417: 1	"operable in a computer system to communicate	"configured in a computer system to communicate data"
	data"	Intrinsic Evidence
		<u>U.S. Patent No. 11093417</u>
		1:54-63; 2:34-46; 2:65-3:6; 5:65-6:12; 6:35-50; 7:4-9; 7:40-60; 7:61-8:9; 8:10-32; 8:59-9:6; 9:7-36; 10:5-30; 10:31-43; 10:44-52; 13:26-45; 13:45-59; 13:60-67; 14:25-36; 15:48-61; 16:31-48; 17:16-24; 17:35-43; 17:44-18:3; 18:4-18; 18:19-35; 19:56-20:3; 20:44-21:9; 21:66-22:14; 22:15-25; 22:26-35; 22:36-62; 23:12-21; 24:26-41; 24:42-54; 24:55-25:3; 25:4-26:6; 26:7-14; 29:21-30:22; 31:29-44; 31:35-32:30; 32:61-33:6; 35:2-28; 38:18-37; 41:39-51; Figs. 1, 2, 3A, 3B, 4A, 4B, 8A, 8B, 9A, 9B, 17A, 17B.
		File Histories
		File histories of U.S. Patents: No. 11093417, No. 7286436, No. 7289386, No. 7532537, No. 7619912, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 10902886, No.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893
		File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415
		Inter Partes Reviews
		IPR2014-00882 (<i>see, e.g.</i> , POPR (Paper 9) at 5, 17), IPR2014-00883 (<i>see, e.g.</i> , POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-01029, IPR2014-01369, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2014-01373, IPR2014-01374, IPR2014-01375, IPR2015-01020, IPR2015-01021, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00561, IPR2017-00562, IPR2017-00577, IPR2017-00587, IPR2017-00667, IPR2017-00668, IPR2017-00692, IPR2017-00730, IPR2018-00303, IPR2018-00362, IPR2018-00363, IPR2018-00364, IPR2018-00365, IPR2020-01042, IPR2020-01044, IPR2020-01421, IPR2022-00062, IPR2022-00639, IPR2022-00064, IPR2022-00236, IPR2022-00237, IPR2022-00615, IPR2022-00639, IPR2022-00711, IPR2022-00744, IPR2022-00745, IPR2022-00996, IPR2022-00999, IPR2022-01427, IPR2022-01428, IPR2023-00203, IPR2023-00204, IPR2023-00205, IPR2023-00405, IPR2023-00406, IPR2023-00454, IPR2023-00455, IPR2023-00847, IPR2023-00883
		Inter Partes Reexaminations
		No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758
		Federal Circuit Appeals

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		International Trade Commission Investigations
		No. 337-TA-1023, No. 337-TA-1089
		<u>Others</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		JEDEC Standards: JEDEC Standard No. 21C, JESD 79-4 Standard, JEDEC 82-31A Standard, JEDEC 82-32A Standard, JESD 248A Standard, JEDEC 79-4C Standard, JESD 79 Standard, JESD 79-2 Standard
		Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008)
		Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '417 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'417: 1, 4, 5, 8, 10	"rank"	"an independent set of one or more memory devices on a memory module that act together in response to command signals, including chip-select signals, to read or write the full bit-width of the memory module"
		Intrinsic Evidence
		<u>U.S. Patent No. 11093417</u>
		2:46-53; 2:65-3:2; 6:51-58; 7:10-16; 7:61-8:9; 8:59-9:6; 9:7-18; 10:5-23; 10:44-52; 14:25-29; 14:37-46; 14:47-55; 14:56-15:4; 15:5-12; 15:13-27; 17:25-34; 17:44-18:3; 18:4-18; 18:19-35; 18:37-39; 18:56-19:10; 19:11-27; 19:28-30; 20:44-58; 21:66-22:14; 22:15-25; 22:26-35; 22:63-23:10; 31:45-32:30; 33:25-43; 33:54-34:6; 34:59-67; Tables 1, 2; Figs.1, 4A, 4B, 8A, 8B, 8C, 8D, 9A, 9B, 10A, 10B, 11A, 11B

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
Claim(s)	Terms for Construction	File Histories File Histories of U.S. Patents: No. 11093417, No. 7286436, No. 7289386, No. 7532537, No. 7619912, No. 7636274, No. 8154901, No. 8001434, No. 8417870, No. 7864627, No. 7881150, No. 8516185, No. 7965578, No. 8081535, No. 7916574, No. 7965579, No. 8072837, No. 8081536, No. 8081537, No. 8359501, No. 8756364, No. 8516188, No. 8787060, No. 8782350, No. 8689064, No. 9128632, No. 9606907, No. 9037774, No. 10217523, No. 9037809, No. 9318160, No. 9858215, No. 9846659, No. 10902886, No. 10860506, No. 10489314, No. 10268608, No. 10290328, No. 10949339, No. 9824035, No. 9659601, No. 9563587, No. 10025731, No. 61409893 File histories of U.S. Patent Applications: No. 2022/0208233, No. 2021/0382834, No. 2021/0271593, No. 2021/0149829, No. 2019/0295675, No. 2021/0225415 Inter Partes Reviews IPR2014-00882 (see, e.g., POPR (Paper 9) at 5, 17), IPR2014-00883 (see, e.g., POPR (Paper 8) at 5-7, 15; POR (Paper 25) at 26), IPR2014-00970, IPR2014-00971, IPR2014-01011, IPR2014-0129, IPR2014-01374, IPR2014-01370, IPR2014-01371, IPR2014-01372, IPR2017-00548, IPR2017-00549, IPR2017-00560, IPR2017-00566, IPR2017-00566, IPR2017-00567, IPR2017-00567, IPR2017-00567, IPR2017-005692, IPR2017-00577, IPR2018-00303, IPR2018-00363, IPR2018-00363, IPR2018-00363, IPR2018-00363, IPR2022-00064, IPR2018-00363, IPR2022-00064, IPR2017-00544, IPR2022-00064, IPR2022-00063, IPR2022-00064, IPR2022-000744, IPR2022-00745, IPR2022-00066, IPR2022-00069, IPR2022-00063, IPR2022-00064, IPR2022-00144, IPR2022-00745, IPR2022-00996, IPR2022-00064, IPR2023-00406, IPR2023-00205, IPR2023-00455, IPR2023-00484, IPR2023-00485, IPR2023-00485, IPR2023-00485, IPR2023-00883

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Inter Partes Reexaminations
		No. 95/000546, No. 95/000577, No. 95/000578, No. 95/000579, No. 95/001337, No. 95/001339, No. 95/001381, No. 95/001758
		Federal Circuit Appeals
		No. 15-126, No. 15-1179, No. 16-1742 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1743 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-1744 (<i>see, e.g.</i> , Netlist Opening Brief (Dkt. No. 20) at 8-13, 30, 40-46; Netlist Reply Brief (Dkt. No. 32) at 15; Opinion and Judgment (Dkt. No. 44) at 2-3), No. 16-2274, No. 16-2666, No. 17-1617, No. 17-1618, No. 18-1676, No. 18-2034, No. 18-2036, No. 18-2037, No. 18-2123, No. 18-2357, No. 19-1720, No. 19-2340, No. 20-1026, No. 21-113, No. 21-114
		Extrinsic Evidence
		<u>District Court Cases</u>
		No. 2:09-cv-06900 (C.D. Cal.), No. 8:13-cv-00996 (C.D. Cal.), No. 8:16-cv-01605 (C.D. Cal.), No. 8:17-cv-01030 (C.D. Cal.), No. 2:12-cv-02319 (E.D. Cal.), No. 2:13-cv-02613 (E.D. Cal.), No. 3:09-cv-05718 (N.D. Cal.), No. 4:08-cv-04144 (N.D. Cal.), No. 4:13-cv-03901 (N.D. Cal.), No. 4:13-cv-03916 (N.D. Cal.), No. 4:13-cv-05889 (N.D. Cal.), No. 4:13-cv-05962 (N.D. Cal.), No. 5:22-mc-80337 (N.D. Cal.), No. 1:09-cv-00165 (D. Del.), No. 1:21-cv-01453 (D. Del.), No. 2:21-cv-00463 (E.D. Tex.), No. 2:22-cv-00203 (E.D. Tex.), No. 2:22-cv-00294 (E.D. Tex.), No. 1:22-cv-00134 (W.D. Tex.), No. 1:22-cv-00136 (W.D. Tex.), No. 6:20-cv-00194 (W.D. Tex.), No. 6:20-cv-00525 (W.D. Tex.), No. 6:21-cv-00430 (W.D. Tex.), No. 6:21-cv-00431 (W.D. Tex.)
		<u>International Trade Commission Investigations</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		No. 337-TA-1023, No. 337-TA-1089 Others JEDEC Standards: JEDEC Standard No. 21C, JESD 79-4 Standard, JEDEC 82-31A Standard, JEDEC 82-32A Standard, JESD 248A Standard, JEDEC 79-4C Standard, JESD 79 Standard, JESD 79-2 Standard Memory Systems: Cache, DRAM, Disk (Bruce Jacob) (2008) Synchronous DRAM Architectures, Organizations, and Alternative Technologies (Bruce Jacob) (December 10, 2002)
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '417 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty. Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in
		the Lead Case, including but not limited to, any expert testimony.
'417: 1	"circuitry being configurable to transfer the burst of N-bit wide data signals between the N-bit wide memory bus and the memory devices in the one of the plurality of N-bit wide ranks in response to	The identified "circuitry" feature in claim 1 is indefinite. For claim 1, the "circuitry" feature is subject to §112, ¶ 6, but there is no disclosure of adequate structure or algorithm for the function of: transfer[ring] the burst of N-bit wide data signals between the N-bit wide memory bus and the memory devices in the one of the plurality of N-bit wide ranks in response to the data buffer control signal. Intrinsic Evidence

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
	the data buffer control signals"	U.S. Patent No. 11093417 No intrinsic evidence because there is no corresponding structure.
		Extrinsic Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '417 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'417: 6, 11	"circuitry includes logic pipelines configurable to enable the data transfers between the memory devices and the memory bus through the circuitry" "circuitry is configurable to	The identified "circuitry" features in claims 6 and 11 are indefinite. For claims 6 and 11, the "circuitry" features are subject to §112, ¶ 6, but there is no disclosure of adequate structure or algorithm for the functions of: (i) the circuitry (of claim 1) includ[ing] logic pipelines configur[ed] to enable the data transfers between the memory devices and the memory bus through the circuitry; and (ii) enabl[ing] the data paths in response to the data buffer control signals so that the burst of N-bit wide data signals are transferred via the data paths.
	enable the data paths in response to the data buffer control signals so that the burst of N-bit wide data	<u>U.S. Patent No. 11093417</u>
	signals are transferred via the data paths"	No intrinsic evidence because there is no corresponding structure.
		Extrinsic Evidence

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '417 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'417: 1	"logic configurable to receive a set of input	Plain and ordinary meaning.
	address and control signals	Intrinsic Evidence
	associated with a read or write memory command	<u>U.S. Patent No. 11093417</u>
	via the address and control signal lines and to output a	No intrinsic evidence because there is no corresponding structure.
	set of registered address and control signals in	Extrinsic Evidence
	response to the set of input address and control signals, the logic is further configurable to output data buffer control signals in response to	Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '417 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
	the read or write memory command"	Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'417: 1, 15	"the read or write	"the read or write memory command"
	command"	Intrinsic Evidence
		<u>U.S. Patent No. 11093417</u>

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		2:65-3:4; 8:26-32; 13:46-59; 19:11-24; 19:51-53; 22:53-56; 23:4-10; 25:4-26:3; 35:13-15; Table 2; Figs. 6A, 6B
		Extrinsic Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '417 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'417: 1	"overall CAS latency of the memory module"	"the delay between: (1) the time when a read command is executed by the memory module, and (2) the time when the first piece of data is made available at an output of the memory module"
		<u>Intrinsic Evidence</u>
		<u>U.S. Patent No. 11093417</u>
		22:36-60
		Extrinsic Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '417 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.

Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'417: 1	"actual operational CAS latency of each of the memory devices"	"the delay between: (1) the time when a read command is executed by each of the memory devices, and (2) the time when the first piece of data is made available at an output of each of the memory devices"
		Intrinsic Evidence
		<u>U.S. Patent No. 11093417</u>
		22:36-60
		Extrinsic Evidence
		Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '417 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
		Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.
'417: 1	"wherein data transfers	Indefinite
	through the circuitry are registered for an amount of	Extrinsic Evidence
	time delay such that the overall CAS latency of the memory module is greater than an actual operational	Micron may rely on testimony of Dr. Harold Stone to explain the technology, state of the art at the time the applications leading to the '417 patent was filed, the level of ordinary skill in the relevant art, and the meaning of this claim element to a person of ordinary skill in the art at the

	Claim(s)	Terms for Construction	Micron's Proposed Construction and Supporting Evidence
ĺ		CAS latency of each of the memory devices"	time of the alleged invention, including whether a person of ordinary skill in the art could discern the boundaries of this claim element with reasonable certainty.
			Micron may also rely on extrinsic evidence identified by Plaintiff or Samsung Defendants in the Lead Case, including but not limited to, any expert testimony.